

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Docket Number (Optional)

SEC.63

Application Number

NEW

Applicant(s)

Yeong-kwan Kim et al.

Filing Date

October 8, 1999

Group Art Unit

TO BE ASSIGNED



U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

MBC	A	Y. Kim et al., "Substrate dependence on the optical properties of Al ₂ O ₃ films grown by atomic layer deposition," Appl. Phys. Lett. 71 (25), 22 December 1997, pages 3604-3606.

EXAMINER

DATE CONSIDERED

9/26/00

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.